



Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 010

Name and Address:

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As declared by the Organization, following is a list of the permanent sites and the phones numbers at which accredited activities are preformed.

- P Haifa
- P1 Leshem +972-4-990-6529

Definitions:

Main site:

A central site where the quality system is controlled for all sites where tests, calibrations or sampling are preformed.

Permanent site (Branch):

Permanent or temporary site existing longer than 6 months where at, or from which, the activities part of the accreditation schedule are preformed



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Schedule of Accreditation

Item	Scope Type	Site	Measurand Instrument, Gauge		Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks	
Calibration – Electrical Quantities - DC and LF						כיוול – גדלים חשמליים - זרם ישר ותדר נמוך			
19	A	P	DC Voltage, Sources	מחוללי מתח בזרם ישר	±100 mV	1 µV/V	Manufacturer instructions SOP 10500 SOP 10650	Standard cell Fluke 732A Fluke DMM 8508A Wavetek MTS 4950	
20	A	P			±1 V	1 µV/V			
21	A	P			±1.018 V	1 µV/V			
22	A	P			±10 V	1 µV/V			
23	A	P			±100 V	1 µV/V			
24	A	P			±1000 V	1.9 µV/V			
25	A	P			[0 to 200 mV]	1µV			
26	A	P			(200 mV to 2 V]	2.6 µV/V			
27	A	P			(2 V to 20 V]	2.0 µV/V			
28	A	P			(0 V to 200 V]	3.0 µV/V			
29	A	P			(200 V to 1100 V]	2.5 µV/V			
30	A	T			[0 to 50 mV]	1 µV			Fluke DMM 8508A
31	A	T			(50 mV to 200 mV]	15 µV/V			
32	A	T			(200 mV to 2 V]	10 µV/V			
33	A	T	(2 V to 20 V]	8.5 µV/V					
34	A	T	(20 V to 200 V]	14 µV/V					
35	A	T	(200 V to 1100 V]	14 µV/V					

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

Flexible scope in analytical tests: Type of matrix, analytes, experimental systems and/or analytical characteristics may be subject to changes, in accordance with the laboratory's approved and documented procedures. For details, please refer to the list of Accredited Tests, available from the laboratory upon request.



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Calibration – Electrical Quantities - DC and LF						כיוול – גדלים חשמליים - זרם ישר ותדר נמוך			
36	A	P	DC Current, Measuring Instruments	זרם ישר, מכשירי מדידה	100 μ A	7.5 μ A/A	Manufacturer instructions SOP 10700	Standard resistors Fluke DMM 8508A Wavetek MTS 4950 Datron Calibrator 4808	
37	A	P			1 mA	6 μ A/A			
38	A	P			10 mA	6 μ A/A			
39	A	P			100 mA	6 μ A/A			
40	A	P			1 A	6 μ A/A			
41	A	P			10 A	30 μ A/A			
42	A	P			Open	0.1 nA			
43	A	P			[0 to 200 μ A]	0.9 nA			
44	A	P			(200 μ A to 2 mA)	9 nA			
45	A	P			(2 mA to 20 mA)	90 nA			
46	A	P			(20 mA to 200 mA)	0.9 μ A			
47	A	P			(200 mA to 2 A)	9 μ A			
48	A	P			(2 A to 11 A)	30 μ A/A			
49	A	P			(11 A to 20 A)	770 μ A/A			
50	A	P			(20 A to 1000 A)	2 mA/A			
51	A	T			Open	0.1 nA			Datron Calibrator 4808
52	A	T			[0 μ A to 20 μ A]	5 nA			
53	A	T			(20 μ A to 50 μ A)	10 nA			

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Calibration – Electrical Quantities - DC and LF					כיוול – גדלים חשמליים - זרם ישר ותדר נמוך		
54	A	T		(50 μ A to 200 μ A]	175 μ A/A		
55	A	T		(200 μ A to 1 mA]	75 nA		
56	A	T		(1 mA to 2 mA]	75 μ A/A		
57	A	T		(2 mA to 10 mA]	0.75 μ A		
58	A	T		(10 mA to 20 mA]	75 μ A/A		
59	A	T		(20 mA to 100 mA]	7.5 μ A		
60	A	T		(100 mA to 200 mA]	75 μ A/A		
61	A	T		(200 mA to 500 mA]	90 μ A		
62	A	T		(500 mA to 2 A]	175 μ A/A		
63	A	T		(2 A to 5 A]	1.2 mA		
64	A	T		(5 A to 10 A]	240 μ A/A		
65	A	T		(10 A to 20 A]	1100 μ A/A		
66	A	T		(20 A to 1000 A]	2 mA/A		
67	A	P	DC Current, Sources	100 μ A	7 μ A/A	Manufacturer instructions	Standard resistors
68	A	P		1 mA	6 μ A/A	SOP 10560	Fluke DMM 8508A
69	A	P		10 mA	6 μ A/A	SOP 10562	Wavetek MTS 4950
70	A	P		100 mA	6 μ A/A	SOP 10650	Datron 4808
71	A	P		1 A	6 μ A/A		Datron 9100 Current coils

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Calibration – Electrical Quantities - DC and LF					כיוול – גדלים חשמליים - זרם ישר ותדר נמוך		
72	A	P		10 A	30 μ A/A		Current clamp
73	A	P		[0 μ A to 200 μ A]	1 nA		
74	A	P		(200 μ A to 2 mA)	9 μ A/A		
75	A	P		(2 mA to 20 mA)	9 μ A/A		
76	A	P		(20 mA to 200 mA)	9 μ A/A		
77	A	P		(200 mA to 2 A)	9 μ A/A		
78	A	P		(2 A to 11 A)	30 μ A/A		
79	A	P		(11 A to 1000 A)	2 mA/A	Manufacturer instructions	Fluke DMM 8508A
80	A	T		[0 μ A to 10 μ A]	6 nA		Wavetek 4953
81	A	T		(10 μ A to 100 μ A)	17 nA		Current clamp
82	A	T		(100 μ A to 200 μ A)	30 nA		Kyoritsu 2003
83	A	T		(200 μ A to 1 mA)	160 nA		
84	A	T		(1 mA to 2 mA)	275 nA		
85	A	T		(2 mA to 10 mA)	1.6 μ A		
86	A	T		(10 mA to 20 mA)	2.75 μ A		
87	A	T		(20 mA to 100 mA)	16 μ A		
88	A	T		(100 mA to 200 mA)	27.5 μ A		
89	A	T		(200 mA to 1 A)	286 μ A		

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Calibration – Electrical Quantities - DC and LF						כיוול – גדלים חשמליים - זרם ישר ותדר נמוך		
90	A	T			(1 A to 2 A]	286 $\mu\text{A/A}$		
91	A	T			(2 A to 11 A]	125 $\mu\text{A/A}$		
92	A	T			(11 A to 1000 A]	17 mA/A		
93	A	P	DC Resistance, Resistors	התנגדות זרם ישר, נגדים	0.001 Ω	75 $\mu\Omega/\Omega$	Manufacturer instructions SOP 10800	Standard resistors
94	A	P			0.01 Ω	20 $\mu\Omega/\Omega$		Datron 4808
95	A	P			0.1 Ω	10 $\mu\Omega/\Omega$		Wavetek 9100
96	A	P			1 Ω	1 $\mu\Omega/\Omega$		Fluke 8508A
97	A	P			10 Ω	2 $\mu\Omega/\Omega$		Wavetek 4950
98	A	P			25 Ω	4 $\mu\Omega/\Omega$		
99	A	P			50 Ω	4 $\mu\Omega/\Omega$		
100	A	P			100 Ω	3 $\mu\Omega/\Omega$		
101	A	P			200 Ω	4 $\mu\Omega/\Omega$		
102	A	P			400 Ω	8 $\mu\Omega/\Omega$		
103	A	P			1 k Ω	5 $\mu\Omega/\Omega$		
104	A	P			10 k Ω	10 $\mu\Omega/\Omega$		
105	A	P			100 k Ω	10 $\mu\Omega/\Omega$		
106	A	P			1 M Ω	10 $\mu\Omega/\Omega$		
107	A	P			10 M Ω	20 $\mu\Omega/\Omega$		

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The certificate attached is an integral part of the schedule and is numbered identically להסמכת מעבדות זהה למספר הנספח וממנו נפרד בלתי חלק מהווה חלק בלתי נפרד ממנו ומספר זה זהה למספר הנספח



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Calibration – Electrical Quantities - DC and LF					כיוול – גדלים חשמליים - זרם ישר ותדר נמוך		
108	A	P		100 MΩ	50 μΩ/Ω		
109	A	P		1 GΩ	0.1 %		Keithley 5155
110	A	P		10 GΩ	2 mΩ/Ω		Keithley 5155
111	A	P		100 GΩ	1 mΩ/Ω		Keithley 5155
112	A	P		1000 GΩ	1 mΩ/Ω		Keithley 5155
113	A	P		(0 to 1Ω]	23 μΩ	Manufacturer instructions SOP 10650	Fluke 8508A
114	A	P		(1 Ω to 20 Ω]	5 μΩ/Ω		
115	A	P		(20 Ω to 200 Ω]	5 μΩ/Ω		
116	A	P		(200 Ω to 2 kΩ]	8 μΩ/Ω		
117	A	P		(2 kΩ to 20 kΩ]	10 μΩ/Ω		
118	A	P		(20 kΩ to 200 kΩ]	10 μΩ/Ω		
119	A	P		(200 kΩ to 2 MΩ]	10 μΩ/Ω		
120	A	P		(2 MΩ to 20 MΩ]	40 μΩ/Ω		
121	A	P		(20 MΩ to 100 MΩ]	220 μΩ/Ω		
122	A	T		(0 to 1 Ω]	45 μΩ		
123	A	T		(1 Ω to 5 Ω]	43 μΩ/Ω		
124	A	T		(5 Ω to 20 Ω]	25 μΩ/Ω		

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Calibration – Electrical Quantities - DC and LF					כיוול – גדלים חשמליים - זרם ישר ותדר נמוך			
243	A	P		20 kHz	43 μV/V			
244	A	P		33 kHz	100 μV/V			
245	A	P		50 kHz	120 μV/V			
246	A	P		100 kHz	160 μV/V			
247	A	P		500 V	100 kHz			160 μV/V
				700 V	50 kHz			160 μV/V
248	A	P		1000 V	50 kHz			160 μV/V
249	A	P		45 Hz	45 μV/V			
250	A	P		1 kHz	45 μV/V			
251	A	P		5 kHz	45 μV/V			
252	A	P		10 kHz	48 μV/V			
253	A	P		15 kHz	48 μV/V			
254	A	P		20 kHz	48 μV/V			
255	A	P		30 kHz	110 μV/V			
256	A	P		33 kHz	110 μV/V			
257	A	P		[0.9 mV to 3 mV]	[40 Hz to 200 kHz]			490 μV/V
				Datron 4922				

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Calibration – Electrical Quantities - DC and LF					כיוול – גדלים חשמליים - זרם ישר ותדר נמוך		
258	A	P		(200 kHz to 500 kHz)	1400 μV/V		
259	A	P		(500 kHz to 1 MHz)	3.3 mV/V		
				(3 mV to 9 mV)			
260	A	P		[40 Hz to 200 kHz]	350 μV/V		
261	A	P		(200 kHz to 500 KHz)	1.1 mV/V		
262	A	P		(500 kHz to 1 MHz)	2.6 mV/V		
				(9 mV to 30 mV)			
263	A	P		[40 Hz to 200 kHz]	220 μV/V		
264	A	P		(200 kHz to 500 KHz)	620 μV/V		
265	A	P		(500 kHz to 1 MHz)	1.6 mV/V		
				(30 mV to 350 mV)			
266	A	P		[40 Hz to 200 kHz]	150 μV/V		
267	A	P		(200 kHz to 500 kHz)	340 μV/V		
268	A	P		(500 kHz to 1 MHz)	860 μV/V		
				(350 mV to 35 V)			
269	A	P		[40 Hz to 200 kHz]	110 μV/V		
270	A	P		(200 kHz to 500 kHz)	350 μV/V		
271	A	P		(500 kHz to 1 MHz)	860 μV/V		

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Calibration – Electrical Quantities - DC and LF					כיוול – גדלים חשמליים - זרם ישר ותדר נמוך		
283	A	P		30 kHz	45 μV/V		
284	A	P		50 kHz	73 μV/V		
285	A	P		100 kHz	74 μV/V		
286	A	P		200 kHz	135 μV/V		
287	A	P		500 kHz	280 μV/V		
288	A	P		700 kHz	720 μV/V		
289	A	P		1MHz	720 μV/V		
290	A	P		10 Hz	130 μV/V		
291	A	P		40 Hz	30 μV/V		
292	A	P		1kHz	29 μV/V		
293	A	P		30 kHz	31 μV/V		
294	A	P		50 kHz	67 μV/V		
295	A	P		60 kHz	67 μV/V		
296	A	P		100 kHz	68 μV/V		
297	A	P		200 kHz	75 μV/V		
298	A	P		500 kHz	279 μV/V		
299	A	P		700 kHz	720 μV/V		

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Calibration – Electrical Quantities - DC and LF					כיוול – גדלים חשמליים - זרם ישר ותדר נמוך		
300	A	P	3 V	1 MHz	720 μ V/V		
301	A	P		50 MHz	20 mV/V		
302	A	P		10 Hz	130 μ V/V		
303	A	P		40 Hz	35 μ V/V		
304	A	P		1 kHz	30 μ V/V		
305	A	P		30 kHz	32 μ V/V		
306	A	P		50 kHz	67 μ V/V		
307	A	P		100 kHz	66 μ V/V		
308	A	P		200 kHz	75 μ V/V		
309	A	P		500 kHz	270 μ V/V		
310	A	P		700 kHz	710 μ V/V		
311	A	P		1 MHz	76 μ V/V		
312	A	P		5 kHz	20 mV/V		
313	A	P		10 MHz	20 mV/V		
314	A	P		20 MHz	20 mV/V		
315	A	P	30 MHz	20 mV/V			

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Calibration – Electrical Quantities - DC and LF					כיוול – גדלים חשמליים - זרם ישר ותדר נמוך		
316	A	P		5 V 1 kHz	28 μV/V		
317	A	P		10 V 10 Hz	47 μV/V		
318	A	P		40 Hz	30 μV/V		
319	A	P		1 kHz	28 μV/V		
320	A	P		30 kHz	29 μV/V		
321	A	P		50 kHz	66 μV/V		
322	A	P		60 kHz	66 μV/V		
323	A	P		100 kHz	66 μV/V		
324	A	P		200 kHz	73 μV/V		
325	A	P		500 kHz	270 μV/V		
326	A	P		700 kHz	710 μV/V		
327	A	P		1 MHz	710 μV/V		
328	A	P		20 V 500 kHz	270 μV/V		
329	A	P		700 kHz	710 μV/V		
330	A	P		1 MHz	710 μV/V		

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331	A	P		30 V 10 Hz	130 μV/V		
332	A	P		40 Hz	38 μV/V		
333	A	P		1 kHz	30 μV/V		
334	A	P		30 kHz	30 μV/V		
335	A	P		50 kHz	66 μV/V		
336	A	P		100 kHz	76 μV/V		
337	A	P		200 kHz	110 μV/V		
338	A	P		100 V 10 Hz	49 μV/V		
339	A	P		40 Hz	42 μV/V		
340	A	P		1 kHz	29 μV/V		
341	A	P		30 kHz	29 μV/V		
342	A	P		50 kHz	66 μV/V		
343	A	P		60 kHz	66 μV/V		
344	A	P		100 kHz	67 μV/V		
345	A	P		300 V 45 Hz	45 μV/V		
346	A	P		1 kHz	43 μV/V		

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347	A	P		5 kHz	47 μV/V		
348	A	P		10 kHz	43 μV/V		
349	A	P		15 kHz	43 μV/V		
350	A	P		20 kHz	43 μV/V		
351	A	P		33 kHz	100 μV/V		
352	A	P		50 kHz	130 μV/V		
353	A	P		100 kHz	160 μV/V		
354	A	P		500 V 100 kHz	160 μV/V		
355	A	P		700 V 50 kHz	160 μV/V		
356	A	P		1000 V 45 Hz	45 μV/V		
357	A	P		1 kHz	45 μV/V		
358	A	P		5 kHz	45 μV/V		
359	A	P		10 kHz	49 μV/V		
360	A	P		15 kHz	49 μV/V		
361	A	P		20 kHz	49 μV/V		
362	A	P		30 kHz	110 μV/V		

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

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The certificate attached is an integral part of the schedule and is numbered identically להסמכת מעבדות



Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 010

Schedule of Accreditation

Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Electrical Quantities - DC and LF					כיוול – גדלים חשמליים - זרם ישר ותדר נמוך		
363	A	P		33 kHz [0.9 mV to 3.0 mV]	110 μV/V		
364	A	P		(40 Hz to 200 kHz)	490 μV/V		
365	A	P		(200 kHz to 500 kHz)	1.4 mV/V		
366	A	P		(500 kHz to 1 MHz)	3.3 mV/V		
367	A	P		(3.0 mV to 9 mV) [40 Hz to 200 kHz]	350 μV/V		
368	A	P		(200 kHz to 500 kHz)	1.1 mV/V		
369	A	P		(500 kHz to 1 MHz)	2.6 mV/V		
370	A	P		(9 mV to 30 mV) [40 Hz to 200 kHz]	220 μV/V		
371	A	P		(200 kHz to 500 kHz)	620 μV/V		
372	A	P		(500 kHz to 1 MHz)	1.6 mV/V		
373	A	P		(30 mV to 350 mV) [40 Hz to 200 kHz]	150 μV/V		
374	A	P		(200 kHz to 500 kHz)	340 μV/V		
375	A	P		(500 kHz to 1 MHz)	860 μV/V		
376	A	P		(350 mV to 35 V) [40 Hz to 200 kHz]	120 μV/V		

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

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Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 010

Schedule of Accreditation

<i>Item</i>	<i>Scope Type</i>	<i>Site</i>	<i>Measurand Instrument, Gauge</i>	<i>Range [Including margins] (Does not include margins)</i>	<i>CMC Expressed as an Expanded Uncertainty (95%)</i>	<i>Reference Documents</i>	<i>Remarks</i>
Calibration – Electrical Quantities - DC and LF					כיוול – גדלים חשמליים - זרם ישר ותדר נמוך		
377	A	P		(200 kHz to 500 kHz]	330 μV/V		
378	A	P		(500 kHz to 1 MHz]	860 μV/V		
379	A	P		[1 V to 3.5 V] 1 MHz to 30 MHz	20 mV/V		
380	A	P		(35 V to 120 V] 10 Hz to 100 kHz	85 μV/V		
381	A	P		(120 V to 500 V] 45 Hz to 100 kHz	180 μV/V		
382	A	P		(500 V to 700 V] 45 Hz to 50 kHz	180 μV/V		
383	A	P		(700 V to 1000 V] 45 Hz to 33 kHz	130 μV/V		
384	A	T		[1 mV to 2 mV] [40 Hz to 100 kHz]	9 mV/V		
385	A	T		(100 kHz to 300 kHz]	14 mV/V		
386	A	T		(300 kHz to 1 MHz] (2 mV to 5 mV]	43 mV/V		
387	A	T		[40Hz to 100 kHz]	9.6 μV		
388	A	T		(100 kHz to 300 kHz]	18 μV		

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

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Schedule of Accreditation

<i>Item</i>	<i>Scope Type</i>	<i>Site</i>	<i>Measurand Instrument, Gauge</i>	<i>Range [Including margins] (Does not include margins)</i>	<i>CMC Expressed as an Expanded Uncertainty (95%)</i>	<i>Reference Documents</i>	<i>Remarks</i>
Calibration – Electrical Quantities - DC and LF					כיוול – גדלים חשמליים - זרם ישר ותדר נמוך		
389	A	T		(300 kHz to 1 MHz) (5 mV to 10 mV]	69 μV		
390	A	T		[40 Hz to 100 kHz]	14 μV		
391	A	T		(100 kHz to 300 kHz]	22 μV		
392	A	T		(300 kHz to 1 MHz) (10 mV to 20 mV]	14 mV/V		
393	A	T		[40 Hz to 100 kHz]	1.4 mV/V		
394	A	T		(100 kHz to 300 kHz]	2.2 mV/V		
395	A	T		(300 kHz to 1 MHz) (20 mV to 50 mV]	10 mV/V		
396	A	T		[40 Hz to 100 kHz]	0.92 mV/V		
397	A	T		(100 kHz to 300 kHz]	2.5 mV/V		
398	A	T		(300 kHz to 1 MHz) (50 mV to 100 mV]	430 μV		
399	A	T		[40 Hz to 100 kHz]	580 μV/V		
400	A	T		(100 kHz to 300 kHz]	1.6 mV/V		
401	A	T		(300 kHz to 1 MHz) (100 mV to 200 mV]	8.5 mV/V		
402	A	T		[40 Hz to 100 kHz]	480 μV/V		

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

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Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 010

Schedule of Accreditation

Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Electrical Quantities - DC and LF				כיוול – גדלים חשמליים - זרם ישר ותדר נמוך			
417	A	T		(5 V to 10 V) [40 Hz to 100 kHz]	0.38 mV/V		
418	A	T		(100 kHz to 300 kHz)	1 mV/V		
419	A	T		(300 kHz to 1 MHz)	5.2 mV/V		
420	A	T		(10 V to 20 V) [40 Hz to 100 kHz]	350 μ V/V		
421	A	T		(100 kHz to 300 kHz)	840 μ V/V		
422	A	T		(300 kHz to 1 MHz)	4.4 mV/V		
423	A	T		(20 V to 50 V) [40 Hz to 30 kHz]	330 μ V/V		
424	A	T		(30 kHz to 100 kHz)	920 μ V/V		
425	A	T		(50 V to 100 V) [40 Hz to 30 kHz]	210 μ V/V		
426	A	T		(30 kHz to 100 kHz)	870 μ V/V		
427	A	T		(100 V to 200 V) [40 Hz to 30 kHz]	180 μ V/V		
428	A	T		(30 kHz to 100 kHz)	860 μ V/V		
429	A	T		(200 V to 500 V) 40 Hz to 33 kHz	370 μ V/V		

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

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The certificate attached is an integral part of the schedule and is numbered identically להסמכת מעבדות זהה למספר הנספח וממנו ומספר זה מהווה חלק בלתי נפרד ממנו



Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 010

Schedule of Accreditation

Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Electrical Quantities - DC and LF					כיוול – גדלים חשמליים - זרם ישר ותדר נמוך		
430	A	T		(500 V to 1000 V] 40 Hz to 33 kHz	300 μV/V		
431	A	P	AC Current Measuring Instruments	1 mA זרם חילופין מכשירי מדידה	300 Hz 240 μA/A	Manufacturer instructions SOP 10574	AVMS Datron 4920, Shunt Adapter Datron 4921, Shunt adapter Rafael 4921R, Current Shunt A40, A40A, Datron Calibrator 4808, Datron 4600, Datron 9100, Current coils
432	A	P			1 kHz 240 μA/A		
433	A	P			5 kHz 240 μA/A		
434	A	P		10 mA 300 Hz	235 μA/A		
435	A	P			1 kHz 235 μA/A		
436	A	P			5 kHz 235 μA/A		
437	A	P		100 mA 300 Hz	235 μA/A		
438	A	P			1 kHz 235 μA/A		
439	A	P			5 kHz 235 μA/A		
440	A	P		1 A 300 Hz	245 μA/A		
441	A	P			1 kHz 245 μA/A		
442	A	P			5 kHz 245 μA/A		
443	A	P		10 A 300 kHz	360 μA/A		

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

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The certificate attached is an integral part of the schedule and is numbered identically זהו חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח



Schedule of Accreditation

Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
<i>Calibration – Electrical Quantities - DC and LF</i>					<i>כיוול – גדלים חשמליים - זרם ישר ותדר נמוך</i>		
444	A	P		1 kHz	360 μ A/A		
445	A	P		5 kHz	360 μ A/A		
				[1 mA to 2 mA]			
446	A	P		[10 Hz to 1 kHz]	240 μ A/A		
447	A	P		(1 kHz to 5 kHz)	250 μ A/A		
				(2 mA to 5 Ma)			
448	A	P		[10 Hz to 1 kHz]	370 μ A/A		
449	A	P		(1 kHz to 5 kHz)	400 μ A/A		
				(5 mA to 20 Ma)			
450	A	P		[10 Hz to 1 kHz]	255 μ A/A		
451	A	P		(1 kHz to 5 kHz)	280 μ A/A		
				(20 mA to 50 mA)			
452	A	P		[10 Hz to 1 kHz]	380 μ A/A		
453	A	P		(1 kHz to 5 kHz)	410 μ A/A		
				(50 mA to 200 mA)			
454	A	P		[10 Hz to 1 kHz]	260 μ A/A		
455	A	P		(1 kHz to 5 kHz)	285 μ A/A		
				(200 mA to 500 mA)			
456	A	P		[10 Hz to 1 kHz]	490 μ A/A		

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

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Schedule of Accreditation

Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Electrical Quantities - DC and LF					כיוול – גדלים חשמליים - זרם ישר ותדר נמוך		
469	A	T		(2 mA to 5 mA) [10 kHz to 1 kHz]	1.3 mA/A		
470	A	T		(1 kHz to 5 kHz)	1.4 mA/A		
471	A	T		(5 mA to 20 mA) [10 Hz to 1 kHz]	0.8 mA/A		
472	A	T		(1 kHz to 5 kHz)	0.9 mA/A		
473	A	T		(20 mA to 50 mA) [10 Hz to 1 kHz]	1.3 mA/A		
474	A	T		(1 kHz to 5 kHz)	1.4 mA/A		
475	A	T		(50 mA to 200 mA) [10 Hz to 1 kHz]	0.8 mA/A		
476	A	T		(1 kHz to 5 kHz)	0.9 mA/A		
477	A	T		(200 mA to 500 mA) [10 Hz to 1 kHz]	1.5 mA/A		
478	A	T		(1 kHz to 5 kHz)	1.7 mA/A		
479	A	T		(500 mA to 2 A) [10 Hz to 1 kHz]	0.96 mA/A		
480	A	T		(1 kHz to 5 kHz)	1.3 mA/A		

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

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Schedule of Accreditation

Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Electrical Quantities - DC and LF					כיוול – גדלים חשמליים - זרם ישר ותדר נמוך		
548	A	P		100 nF 120 Hz	0.4 mF/F		
549	A	P		1 kHz	0.3 mF/F		
550	A	P		10 kHz	1 mF/F		
551	A	P		100 kHz	3 mF/F		
552	A	P		1 μF 120 Hz	0.6 mF/F		
553	A	P		1 kHz	0.3 mF/F		
554	A	P		10 kHz	0.8 mF/F		
555	A	P		1 pF 1 kHz	2 mF/F		
556	A	P		1 MHz	4 mF/F		
557	A	P		10 MHz	13 mF/F		
558	A	P		13 MHz	13 mF/F		
559	A	P		10 pF 1 kHz	0.3 mF/F		
560	A	P		1 MHz	0.8 mF/F		
561	A	P		10 MHz	2.5 mF/F		
562	A	P		13 MHz	2.5 mF/F		

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Schedule of Accreditation

Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Electrical Quantities - DC and LF					כיוול – גדלים חשמליים - זרם ישר ותדר נמוך		
579	A	P		1 μ F 120 Hz	0.6 mF/F		
580	A	P		1 kHz	0.3 mF/F		
581	A	P		10 kHz	0.8 mF/F		
582	A	P		1 pF 1 kHz	2 mF/F		
583	A	P		10 pF 1 kHz	0.3 mF/F		
584	A	P		100 pF 1 kHz	0.6 mF/F		
585	A	P		1000 pF 1 KHz	0.3 mF/F		
586	A	P	Inductance, Measuring Instruments	100 μ H 1 KHz	0.7 mF/F	Manufacturer instructions SOP 10980	GR Inductors
587	A	P		1 mH 1 KHz	0.3 mF/F		
588	A	P		10 mH 1 KHz	0.4 mF/F		
589	A	P		100 mH 1 kHz	0.3 mF/F		
590	A	P		1 H 1 kHz	0.6 mF/F		
591	A	P		10 H 400 Hz	0.5 mF/F		

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

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The certificate attached is an integral part of the schedule and is numbered identically להסמכת מעבדות



Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 010

Schedule of Accreditation

Item	Scope Type	Site	Measurand Instrument, Gauge		Range [Including margins] (Does not include margins)		CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks	
Calibration – Electrical Quantities - DC and LF							כיוול – גדלים חשמליים - זרם ישר ותדר נמוך			
592	A	P	Inductance, Inductors	השראות, משרניים	100 μ H	1 kHz	0.7 mF/F	Manufacturer instructions SOP 10985	LCR GR Tech Inductors	
593	A	P			1 mH	1 kHz				0.3 mF/F
594	A	P			10 mH	1 kHz				0.4mF/F
595	A	P			100 mH	1 kHz				0.4 mF/F
596	A	P			1 H	1 kHz				0.7 mF/F
597	A	P			10 H	400 Hz				0.5 mF/F
598	A	P			Frequency, Sources	תדר, מחוללים				100 kHz
599	A	P	1 MHz	10^{-11} for 3 h						
600	A	P	5 MHz	10^{-11} for 3 h						
601	A	P	10 MHz	10^{-11} for 3 h						
602	A	P;T	[1 Hz to 10 kHz]	10 μ Hz for 1 s						
603	A	P;T	(10 kHz to 30 MHz)	10^{-9} for 1 s						
604	A	P;T	(30 MHz to 80 MHz)	10^{-11} Hz for 1 s						

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

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The certificate attached is an integral part of the schedule and is numbered identically להסמכת מעבדות זהה למספר הנספח



Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 010

Schedule of Accreditation

<i>Item</i>	<i>Scope Type</i>	<i>Site</i>	<i>Measurand Instrument, Gauge</i>	<i>Range [Including margins] (Does not include margins)</i>	<i>CMC Expressed as an Expanded Uncertainty (95%)</i>	<i>Reference Documents</i>	<i>Remarks</i>
Calibration – Electrical Quantities - DC and LF					כיוול – גדלים חשמליים - זרם ישר ותדר נמוך		
605	A	P	AC charge amplification. Charge amplifiers	הגברת מטען חשמלי. מגברי מטען 40 Hz – 10 kHz Minimum input 10 pC RMS Maximum output 1 V RMS	0.2 %	Manufacturer instructions SOP 11300	Calibration of voltage output per charge input

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

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The certificate attached is an integral part of the schedule and is numbered identically זהו למספר הנספח וממנו נפרד בלתי חלק מהווה חלק בלתי נפרד ממנו ומספר זה נוסף לנספח זה המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספר זה נוסף לנספח זה המצורפת לנספח זה



Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 010

Schedule of Accreditation

Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Electrical Quantities - RF Frequency, Time					כיוול – גדלים חשמליים - תדר גבוה, זמן		
606	A	P;T	Frequency. Sources	תדר, מקורות (80 MHz to 1500 MHz)	1.2 mHz for 10 s	Manufacturer instructions SOP 10924	HP 105 B, HP 58503A, HP5245M, HP 3335 A, HP 3325 GPS HP 58503 A
607	A	P;T		(1500 MHz to 6 GHz)	2 mHz for 10 s		
608	A	P;T		(6 GHz to 50 GHz)	$3 \cdot 10^{-13}$ for 10 s		
609	A	P;T	Frequency. Measuring Instruments	תדר, מכשירי מדידה (1 Hz to 100 Hz)	25 μ Hz for 1 s	Manufacturer instructions	HP 105 B, HP 58503A, HP5245M, HP 3335 A, HP 3325, GPS HP 58503 A
610	A	P;T		(100 Hz to 10 kHz)	11 μ Hz for 1 s		
611	A	P;T		(10 kHz to 30 MHz)	$2 \cdot 10^{-10}$ for 1 s		
612	A	P;T	Time markers function, sine wave	מדידת דיוק ציר אופקי במשקף תנודות בעזרת גל סינוס [0.2 ns to 1 ns]	0.21 ps	Manufacturer instructions SOP 10974	Wavetek 9500B
613	A	P;T		(1 ns to 9 ns)	1.8 ps		
614	A	P;T	Time markers function, square wave	מדידת דיוק ציר אופקי במשקף תנודות בעזרת גל מרובע [10 ns to 100 μ s]	0.8 ns	Manufacturer instructions SOP 10974	Wavetek 9500B
615	A	P;T		(100 μ s to 1 ms)	1.6 ns		
616	A	P;T		(1 ms to 55 s)	80 μ s		
617	A	P;T	DC Voltage into 1 M Ω	מדידת דיוק ציר אנכי במשקף תנודות בכניסה 1 M Ω 1 mV to 190 V	25 μ V + 0.25 mV/V OR	Manufacturer instructions SOP 10700	FLUKE 9500 & active heads OR - of reading
618	A	P;T	DC Voltage into 50 Ω	מדידת דיוק ציר אנכי במשקף תנודות בכניסה 50 Ω 1 mV to 5V	25 μ V + 0.25 mV/V OR		
619	A	P;T	Square Wave Voltage into 1 M Ω	מדידת דיוק ציר אנכי במשקף תנודות בכניסה 1 M Ω 1 kHz [6 mV to 210 V]	2.9 mV/V	Manufacturer instructions SOP 10974	

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

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The certificate attached is an integral part of the schedule and is numbered identically להסמכת מעבדות



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Schedule of Accreditation

Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Electrical Quantities - RF Frequency, Time					כיוול – גדלים חשמליים - תדר גבוה, זמן		
620	A	P;T	Input Resistance	50 Ω	1 mΩ/Ω	Manufacturer instructions	
621	A	P;T		1 MΩ	1 mΩ/Ω	SOP 10650	
622	A	P;T	Bandwidth (50 Ω & 1 MΩ)	[1 kHz to 20 MHz] 100 mV to 3V	0.023 MHz/MHz (2.3 %)	Manufacturer instructions SOP 10974	
623	A	P;T		(20 MHz to 500 MHz) 200 mV to 2V	0.015 MHz/MHz (1.5 %)		
624	A	P;T		(500 MHz to 6 GHz) 200 mV to 2V	0.07 GHz/GHz (0.7%)		
625	A	P;T		(6 GHz to 50 GHz] 632.5 mV	0.1 GHz/GHz (10 %)		
626	A	P;T	Input Capacitance	18 pF to 92 pF	30 mF/F	Manufacturer instructions SOP 10650	
627	A	P;T	Transition Time, Oscilloscopes	25 mV to 2.2 V >70 ps	5.6 ps	Manufacturer instructions SOP 10974	
628	A	P;T	Transition Time, Pulse generators	400 mV >19 ps	2.5 ps	Manufacturer instructions SOP 10974	

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

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The certificate attached is an integral part of the schedule and is numbered identically להספרי הזה ומספרה זה מהווה חלק בלתי נפרד ממנו ומספרה זה למספר הנספח



Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 010

Schedule of Accreditation

Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks	
Calibration – Electrical Quantities – LF Single Phase Electrical Power and Energy					כיוול – גדלים חשמליים - הספק ואנרגיה חשמלית חד מופעית בתדר נמוך			
629	A	P;T	Power, Sources	הספק, מקורות	[10 MHz to 18 GHz]	50 mW/W	Manufacturer instructions SOP 10925	
630	A	P;T			(18 GHz to 40 GHz]	51 mW/W		
631	A	P;T			(40 GHz to 50 GHz]	65 mW/W		
632	A	P;T	Power, Power Sensors Cal Factor	הספק, מקדם כיוול רגשי הספק	[100 MHz to 8 GHz]	20 mW/W	Manufacturer instructions SOP 10945 Manufacturer instructions	
633	A	P;T			(8 GHz to 32 GHz]	30 mW/W		
634	A	P;T			(32 GHz to 43 GHz]	35 mW/W		
635	A	P;T			(43 GHz to 50 GHz]	42 mW/W		
636	A	P;T	Power Power Meter 1 mW output	הספק, מדי הספק, יציאה 1 mW	50 MHz	5.4 mW/W	SOP 10923	Reference Power Sensor
637	A	P;T	Attenuation, Attenuators	הנחתה מנחתים	[0.1 GHz to 2 GHz] [0 dB to 15 dB]	0.04 dB	Manufacturer instructions SOP 10928	436A-E40 Microwave Power Sensor System HP 8350B Sweep Generator HP 436A Power Meter HP 8481A, 8484 Power References Sensors
638	A	P;T			(15 dB to 35 dB]	0.09 dB		
639	A	P;T			(35 dB to 60 dB]	0.12 dB		
640	A	P;T			(2 GHz to 6 GHz] [0 to 15 dB]	0.06 dB		
641	A	P;T			(15 to 35 dB]	0.12 dB		
642	A	P;T			(35 to 60 dB]	0.21 dB		
643	A	P;T			(6 GHz to 14 GHz] [0 dB to 15 dB]	0.08 dB		

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Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 010

Schedule of Accreditation

Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Electrical Quantities – LF Single Phase Electrical Power and Energy					כיוול – גדלים חשמליים - הספק ואנרגיה חשמלית חד מופעית בתדר נמוך		
644	A	P;T		(15 dB to 35 dB)	0.19 dB		
645	A	P;T		(35 dB to 60 dB)	0.21 dB		
				(14 GHz to 18 GHz]			
646	A	P;T		[0 dB to 15 dB]	0.1 dB		
647	A	P;T		(15 dB to 35 dB]	0.13 dB		
648	A	P;T		(35 dB to 60 dB]	0.23 dB		
649	A	P;T	Amplitude Modulation (AM), Depth of Signals	אפנון משרעת, עומק אפנון	Carrier frequency: [sine 100 Hz to 50 GHz] Modulation frequency: [1 Hz to 250 kHz sine and square] Modulation depth: [5% to 95%] Ratio: Carrier/Rate [10 to 50·10 ⁹]	1 % Manufacturer instructions SOP 10962	Agilent PSA spectrum Analyzer, model E4448A

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

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Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Mechanical Quantities – CMM Measuring Machines					כיוול – גדלים מכניים – מכשירי מדידה תלת ממדיים		
658	A	P,T	Length, CMM Measuring Machine אורך, מכונת מדידה תלת ממדיות	20 mm to 2000 mm	[0.2+2L] μm	ISO 10360-2 SOP 10025	L in meters Check Master Accurate Ball Gauge
659	A	P,T		125 mm to 1000 mm	[0.16+1.2L] μm	ISO 10360-2 SOP 10025	Gauge Blocks

Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Mechanical Quantities – Form, Angle					כיוול – גדלים מכניים – צורה, זווית		
660	A	P	Form, Flatness, צורה, שטיחות, מישור אופטי	Up to 0.6 μm]	0.09 μm	A-A-58051 JIS B 7430	For optical flats with a diameter up to 100 mm
661	A	P	Optical Flats	(0.6 μm to 1.2 μm]	0.12 μm	Manufacturer instructions SOP 9150104	For surfaces with a diameter up to 100 mm
662	A	P,T	Form, Flatness, Surface Plates צורה, שטיחות, לוחות שטוחים	Up to 2 mm	2.1 μm	DIN 876 parts 1 and 2 BS 817 ASME B89.3.7 ISO 8512-part 2 SOP 10032	Electronic Levels L in meters diagonal Granite, Cast Iron For surfaces up to 2000 mm in diagonal
663	A	P	Form, Straightness Straightedges צורה, ישרות, סרגל ישרות	Up to 500 mm	3 μm	DIN 874 part 2 SOP 9150114	Surface plate, electronic gauge head
664	A	P	Form, Straightness, Knife edge צורה, ישרות, סרגל שורה	Up to 500 mm	0.8 μm	DIN 874 part 2 SOP 9150121	Surface plate, electronic gauge head, Square Block

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

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Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Mechanical Quantities – Form, Angle					כיוול – גדלים מכניים – צורה, זווית		
686	A	P	Angle, Digital Levels זווית, פלט אלקטרוני פלט דיגיטלי	Up to 360°	2.9'	MIL-V-3144B Manufacturer instructions SOP 9150118	
687	A	P	Sine Bar סרגל סינוס	0° -45°	6.3 "	BS 3064 SOP 9150119	Gauge blocks, angle gauge blocks
688	A	P	Parallelism of roll axes מקבילות בין צירי הגליל	0° -45°	0.7 μm		
689	A	P	Flatness of working surface שטוחות משטח עבודה	0° -45°	0.8 μm		
690	A	P	Parallelism of working surface to reference plane מקבילות בין משטחי עבודה למישור הייחוס	0° -45°	0.8 μm		
691	A	P	Distance between roll axes מרחק בין צירי הגלילים	0° -45°	3.8 μm	SOP 9150119	
692	A	P	Inclinometer מד שיפוע	45 °	3.1"	Manufacturer instructions SOP 10027	Sine bar, gauge blocks, DVM
693	A	P	Revolution per minute מהירות סיבוב,	[100 to 500] RPM	0.6% OR	Manufacturer instructions SOP 10044	Counter
694	A	P	Contact Tachometers מד מהירות סיבוב במגע	(500 to 10000) RPM	0.03% OR		OR –of reading
695	A	P	Revolution per minute מהירות סיבוב,	[5 to 10,000] RPM	0.05% OR	Manufacturer instructions SOP 10044	Counter
696	A	P	Optical Tachometers מד מהירות סיבוב אופטי	(10,000 to 100,000) RPM	0.02% OR		OR –of reading

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Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Mechanical Quantities - Hardness Meters					כיוול – גדלים מכניים - מדי קושיות		
697	A	P,T	Rockwell hardness scale, Rockwell hardness testing machines	HRA קשיות רוקוול, מכונות לבדיקת קשיות רוקוול	[20 to 84] 0.4 HRA	ASTM E-18 SOP 10018	Indirect verification, i.e. Calibration by comparison to reference materials.
698	A	P,T		HRC	[20 to 65] 0.4 HRC		
699	A	P,T		HRBW	[40 to 100] 1.0 HRBW		
700	A	P,T		HREW	[70 to 100] 0.55 HREW		
701	A	P,T		HRFW	[60 to 100] 0.5 HRFW		
702	A	P,T		HR15N	[70 to 92] 0.5 HR15N		
703	A	P,T		HR30N	[42 to 82] 0.5 HR30N		
704	A	P,T		HR15TW	[74 to 93] 0.4 HR15TW		
705	A	P,T		HR30TW	[43 to 83] 0.7 HR30TW		
706	A	P		Shore hardness testing instruments - durometers. SHORE A	מכשירים למדידת קשיות בשיטת שור - דורמטרים. שור A		
707	A	P	Indenter extension	אורך החודרן	[2.46 to 2.54] mm 0.045 mm		
708	A	P	Indenter diameter	קוטר החודרן	[0.76 to 0.82] mm 0.002 mm		
709	A	P			[1.1 to 1.4] mm 0.002 mm		
710	A	P	Indenter angle	זווית החודרן	[34.75° to 35.25°] 0.07°		

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Item	Scope Type	Site	Measurand Instrument, Gauge		Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Mechanical Quantities - Hardness Meters						כיוול – גדלים מכניים - מדי קושיות		
711	A	P	Shore hardness testing instruments - durometers. SHORE D	מכשירים למדידת קשיות בשיטת שור - דורמטרים. שור D	[10 to 100] Shore D	0.3 SHORE D	ASTM D-2240 ISO 18898 SOP 10028	Balance and device for durometer calibration Profile projector
712	A	P	Indenter extension	אורך החודרן	[2.46 to 2.54] mm	0.045 mm		
713	A	P	Indenter diameter	קוטר החודרן	[1.1 to 1.4] mm	0.002 mm		
714	A	P	Indenter radius	רדיוס החודרן	[0.088 to 0.112] mm	0.002 mm		
715	A	P	Indenter angle	זווית החודרן	[29.5° to 30.5°]	0.07°		

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Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Mechanical Quantities - Length					כיוול – גדלים מכניים - אורך		
716	A	P	Length, Gauge Blocks (by Comparison) אורך, מקבילונים	[0.5 mm to 10 mm]	#A ##B 0.085 μm 0.15 μm	SOP 9150112	Gauge Block Comparator # Class A uncertainties apply to the measurement of length of gauges by comparison with grade K standards of a similar material ## Class B uncertainties apply to the measurement of length of gauges by comparison with grade 0 standards of a similar material
717	A	P		(10 mm to 25 mm)	0.11 μm 0.18 μm	DIN 861	
718	A	P		(25 mm to 60 mm)	0.14 μm 0.22 μm	JIS B 7506	
719	A	P		(60 mm to 90 mm)	0.19 μm 0.27 μm	BS 4311	
720	A	P		(90 mm to 100 mm)	0.25 μm 0.34 μm	ISO 3650	
721	A	P		(100 mm up to 250 mm)	0.55 μm		
722	A	P	Length, Gauge Blocks Comparators אורך, קומפרטור למקבילונים	[0.5 mm to 250 mm]	[0.05 + 0.3L] μm	SOP 10053 Based on EURAMET/cg-02	Set of 6 pairs of gauge blocks including 6 mm bridge shaped gauge block Grade K gauge blocks L in meters
723	A	P	Length, Micrometer extension rod אורך, מוטות הארכה למיקרומטר	[25 mm to 600 mm]	0.5 μm	GGG-C-105-1987	Gauge block, Measuring machines L in meters
724	A	P		(25 mm to 1000 mm)	[1 + 1.2L] μm	DIN 861-1980 SOP 9150127	
725	A	P	Diameter, Plain Ring Gauges, parallel קוטר, מדידי טבעת חלקה	[1.5 mm to 90 mm]	0.3 μm	SOP 9150123 Based on DIN 2250 part 1 DIN 2250 part 2	Gauge Blocks Measuring machines
726	A	P		(90 mm to 300 mm)	0.4 μm	DIN 2254 DIN 2254 DIN 7162	

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Schedule of Accreditation

Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Mechanical Quantities - Length						כיוול – גדלים מכניים - אורך	
						DIN 7163 ASME B1.1 ASME B1.2	
727	A	P	Diameter,	[0.7 mm to 25 mm]	1.0 μm	SOP 10050	Gauge Blocks
728	A	P	Plain Plug Gauges	(25 mm to 200 mm)	1.0 μm	Based on MIL-STD-120 DIN 7164 ASME B1.1, ASME B1.2	Measuring machines
729	A	P	Diameter, Measuring Pins	[0.7 mm to 25.4 mm]	0.8 μm	MIL-STD-120 DIN 2269 SOP 10050	Gauge Blocks Measuring machines
730	A	P	Diameter, Pitch. Thread Measuring Wires,	[0.1155 mm to 5.7735 mm]	0.3 μm	ASME B89.6 SOP 10048	Measuring machine
731	A	P	Diameter, Pitch. Thread Plug Gauges, Parallel	[0.8mm to 300 mm]	1 μm	ISO 228/1/2 ISO 1502 ISO 2903 ISO 2904 BS 84 BS 919/1/3 409/1/2 ASME B1.2 ASME B1.1 ASME B1.9 SOP 9150124	Gauge Blocks Measuring machine

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

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Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Mechanical Quantities - Length					כיוול – גדלים מכניים - אורך		
732	A	P	Diameter, Pitch. Thread Plug Gauges, Taper	קוטר אפקטיבי, מדידי הברגה זכר, קוני	[0.8 mm to 77 mm]	3.9 μm	SOP 9150124 Flank angle 60°
733	A	P	Diameter, Pitch Thread Ring gauges Parallel	קוטר אפקטיבי, מדידי הברגה טבעת, מקביל	[5 mm to 200 mm]	1.8 μm	ISO 228/1/2 ISO 1502 ISO 2903 ISO 2904 BS 84 BS 919/1/2/3 ASME B1.1, ASME B1.2 ASME B1.9 SOP 9150128 Functional Inspection (GO-NOT GO) in the range up to 25.4 mm may be provided Wear and setting plugs Measuring machine, gauge blocks
734	A	P	Diameter, Internal Dial Bore Gauge, Built in	קוטר פנימי, מד קדח, חוגן מובנה, אינטרטסט	Up to 150 mm	8.4 μm	Manufacturer instructions JIS 7515 SOP 10014 Measuring machine Indicator Tester
735	A	P	Diameter, Internal, Dial bore gauge	קוטר פנימי, מד קדח גשר	[4 mm to 400 mm]	0.9 μm	Manufacturer instructions SOP 9150111 Electronic Gauge
736	A	P	Diameter, Internal, Dial bore gauge, Split Pin	קוטר פנימי, מד קדח פין מפציל	[0.5 mm up to 41.3 mm]	2.0 μm	SOP 9150110 Outside micrometer, gauge blocks
737	A	P	Length, Vernier, Dial and Digital Caliper	אורך, זחון וורניר, חוגן ודיגיטלי	Up to 2000 mm]	(8 + 5 L) μm	JIS B 7507 DIN 862 BS 887 SOP 9150105 Check master; length bars, gauge blocks L in meters BMC values stand for instruments that have resolution of 0.001 mm

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

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Schedule of Accreditation

Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Mechanical Quantities - Length					כיוול – גדלים מכניים - אורך		
738	A	P;T	Length, Height Gauge אורך, מד גובה	Up to 1000 mm]	3 μm	JIS B 7517 BS 1643 SOP 10051	Check master; length bars, gauge blocks, indicator tester. CMC values stand for instruments that have resolution of 0.0001 mm
739	A	P	Length, Micrometer External אורך, מיקרומטר חיצוני	[Up to 400 mm]	(1.6+5.5L) μm	JIS B 7502 JIS B 7520 DIN 863 part 1 BS 870 SOP 10052	Gauge blocks, micrometer setting rods L in meters
740	A	P		[400 mm to 1000 mm]	(3+1.1L) μm		
741	A	P	Length, Micrometer Head אורך, ראש מיקרומטרי	Up to 50 mm]	1.1 μm	JIS B 7504 BS 1734 DIN 863 part 2 SOP 10021	Gauge blocks, electrical gauge head L in meters
742	A	P	Length, Micrometer Depth אורך, מיקרומטר עומק	Up to 300 mm]	(2 μm +10L) μm	JIS B 7504 DIN 863 part 2 BS 1734 SOP 9150106	Gauge Blocks L in meters
743	A	P	Diameter, Internal Three point internal micrometer קוטר פנימי, מיקרומטר פנימי 3 נקודות	Up to 90 mm]	1.6 μm	DIN 863 part 4 SOP 9150129	Plain gauge Indication 0.001 mm
744	A	P		(90 mm to 200 mm]	1.8 μm		Indication 0.01 mm
745	A	P	Length, Inside micrometer אורך מיקרומטר פנימי	Up to 75 mm]	1.8 μm	DIN 863 SOP 10023	Gauge blocks, Gauge blocks accessories

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

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The certificate attached is an integral part of the schedule and is numbered identically להסמכת מעבדות זהה למספר הנספח



Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 010

Schedule of Accreditation

Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks	
Calibration – Mechanical Quantities - Length					כיוול – גדלים מכניים - אורך			
746	A	P	Diameter, Internal, Three point internal micrometer with gauge block accessories	קוטר פנימי, מיקרומטר פנימי 3 נקודות עם אביזרי מקבילונים	Up to 300 mm]	11.0 μm	SOP 9150129	
747	A	P	Length, Dial Gauge, lever	אורך, חוגן מנופי	Up to 0.8 mm]	0.8 μm	JIS B 7509 DIN 879 part 1 BS 907	Indication 0.001 mm
748	A	P			Up to 0.2 mm	1 μm	JIS B 7533 BS 2795	Indication 0.002 mm
749	A	P			(0.8 mm to 3 mm]	2.4 μm	JIS B 7503 DIN 878- DIN 2270 SOP 9150103	Indication 0.01 mm Indicator Tester
750	A	P	Length , Dial indicator	אורך, חוגן	Up to 0.05 mm	0.4 μm	JIS B 7509 DIN 879 part 1	Indication 0.005 mm
751	A	P			Up to 5 mm	0.42 μm	BS 907 JIS B 7533	Indication 0.001 mm
752	A	P			Up to 100 mm]	1 μm	BS 2795 DIN 2270	Indication 0.01 mm
753	A	P			(100 mm to 150 mm]	(0.85+5.5L) μm	DIN 878 JIS B 7503 SOP 9150107	Indicator Tester L in meters
754	A	P	Length, Indicator Tester	אורך, בודק חוגנים	Up to 25 mm	0.5 μm	Manufacturer instructions	Indication 0.001 mm
755	A	P			Up to 5 mm	0.3 μm	SOP 9150134	Indication 0.0002 mm Gauge blocks

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Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 010

Schedule of Accreditation

Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Mechanical Quantities - Length					כיול – גדלים מכניים - אורך		
756	A	P	Length, LVDT אורך, מתמר אורך	Up to 50 mm	27 µm	Manufacturer instructions SOP 10022	Indicator Tester DVM
757	A	P	Length Electronic probe אורך גשש אלקטרוני	Up to 60 mm	0.12 µm		Gauge blocks
758	A	P	Length, Height Gauge Micrometric אורך, מד גובה מיקרומטרי	Up to 300 mm	3 µm	Manufacturer instructions SOP 9150109	Gauge blocks, electronical gauge head
759	A	P	Length, Horizontal Measuring Machine אורך, מכונת מדידה	Up to 100 mm	0.14 µm	Manufacturer instructions SOP 10029	Indication 0.00001 mm Measuring machine range up to 1000 mm
760	A	P		Up to 200 mm	(0.17+1.8L)µm		Indication 0.0001 mm
761	A	P	Length, Sieves אורך, נפות אריג	Up to aperture of 4.75 mm	3 µm	ASTM – E11 ISO 3310-1 SOP 10054	Profile Projector Micrometer Head
762	A	P	P מד מרווח אורך	Up to 1 mm	0.5 µm	JIS B 7524 DIN 2275 SOP 10055	Certo
763	A	P;T	Magnification Profile projector הגדלה מטול אופטי	Up to 100 M	0.0092%	Manufacturer instructions JIS B 7184 SOP 10026	Optical scale M - Magnification Screen sizes up to 300 mm

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The certificate attached is an integral part of the schedule and is numbered identically להסמכת מעבדות זהה למספר הנספח



Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 010

Schedule of Accreditation

Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Physical Quantities - Force, Torque					כירל – גדלים פיזיקליים - כח, מומנט		
764	A	P	Force, Dynamometers	כוח, מדדי כוח [0.5 N to 210 N]	0.008% OR + 0.0008 N	ISO 7500-1 ISO 376	Comparison vs. weights
765	A	P		(210 N to 1961 N]	0.008% OR + 0.05 N		Comparison vs. weights
766	A	P		(1961 N to 3130 N]	3.3 N	SOP 9015031	Comparison vs. proving rings and load cells
767	A	P		(3130 N to 6410 N]	4.7 N	SOP 90150318	
768	A	P		(6410 N to 9700 N]	7.1 N		
769	A	P		(9.7 kN to 12.9 kN]	9.5 N		
770	A	P		(12.9 kN to 17.6 kN]	13.8 N		
771	A	P		(17.6 kN to 18.8 kN]	15 N		
772	A	P		(18.8 kN to 23.1 kN]	20 N		
773	A	P;T		(23.1 kN to 26.3 kN]	22 N		
774	A	T		(26.3 kN to 38.55 kN]	29 N		
775	A	P;T		(38.550 kN to 42.17 kN]	42 N		
776	A	P;T		(42.17 kN to 53.13 kN]	55 N		
777	A	P		(53.13 kN to 65.18 kN]	74 N		
778	A	P		(65.18 kN to 90.6 kN]	94 N		
779	A	P		(90.6 kN to 274.61 kN]	500 N		
780	A	P		(274.61 kN to 367.8 kN]	700 N		

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

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Schedule of Accreditation

Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Physical Quantities - Force, Torque					כיוול – גדלים פיזיקליים - כח, מומנט		
781	A	P		(367.8 kN to 450.0 kN] kN	900 N		
782	A	P		(450 kN to 4.4 MN]	11 kN		
783	A	T	Force, Material Testing Machines	(0.05 kN to 0.5 kN]	0.37 kN	Manufacturer instructions SOP 10005	Comparison vs. load cells
784	A	T	Presses	(0.5 kN to 1 kN]	0.79 kN		
785	A	T		(1 kN to 2 kN]	1.9 kN		
786	A	T		(24.5 kN to 98 kN]	0.1 % OR +98 N		
787	A	T		(98 kN to 500 kN]	0.1% OR + 1 kN		
788	A	T		(500 kN to 4.4 MN]	(0.1% OR +15.6) kN		
789	A	P, P1	Torque,	(0.1 N·m to 2 N·m]	0.01 N·m	ISO 6789 SOP 10033	Torque Tester
790	A	P,P1	Torque Wrenches	(2 N·m to 10 N·m]	0.08 N·m		
791	A	P,P1		(10.0 N·m to 25 N·m]	0.17 N·m		
792	A	P,P1		(25 N·m to 100 N·m]	0.41 N·m		
793	A	P,P1		(100 N·m to 400 N·m]	1.3 N·m		
794	A	P,P1		(400 N·m to 800 N·m]	2.1 N·m		
795	A	P, P1		(800 N·m to 1100 N·m]	2.9 N·m		
796	A	P	Torque,	[0.1 N·m to 1 N·m]	0.0026 N·m	Manufacturer instructions Euramet/CG-14/V.01	Standard weights and arms
797	A	P	Torque Testers	(1 N·m to 34 N·m]	0.05 N·m		

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Schedule of Accreditation

Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Physical Quantities - Force, Torque					כיוול – גדלים פיזיקליים - כח, מומנט		
798	A	P		(34 N·m to 340 N·m]	0.34 N·m	SOP 90150320	
799	A	P		(340 N·m to 1062 N·m]	2.1 N·m		
800	A	P		(1062 N·m to 1356 N·m]	3.3 N·m		

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Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Physical Quantities - Humidity					כיוול – גדלים פיזיקליים - לחות		
812	A	P	Temperature, Relative Humidity/ Temperature Gauges טמפרטורה רגשי לחות / טמפרטורה	5 °C to 50 °C at 5% rh to 95% rh	0.25 °C	IEC 60751 SOP 10152	By reference to Pt100 in HygroGen chamber
813	A	T	Relative Humidity, Humidity Chambers, Humidity Controller לחות יחסית, בקרים לתאי סביבה	30 % rh at 30 °C-50 °C	2.6 % rh	SOP 10152 SOP 9015037	Humidity Sensor Comet. Humidity controller error is measured in one point adjacent to the controller sensor. The error does not comprise the non-uniformity in the chamber.
814	A	T		30% rh-50% rh 30 °C-50 °C	3.1% rh		
815	A	T		50% rh-90% rh 30 °C-50 °C	3.6% rh		
816	A	T	Relative Humidity, Humidity Chambers, Uniformity of Humidity. לחות יחסית, תאי לחות, אחידות הלחות	30 % rh at 30 °C-50 °C	4.0 % rh	SOP 10152 SOP 9015037	Uniformity of Humidity is characterized by RH values spread inside the chamber and does not comprise chamber controller errors.
817	A	T		30% rh-50% rh 30 °C-50 °C	5.2% rh		
818	A	T		50% rh-90% rh 30 °C-50 °C	7.2% rh		

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Schedule of Accreditation

Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks	
Calibration – Physical Quantities - Liquid and Air Flow					כיוול – גדלים פיזיקליים – זרימה, נוזל ואוויר			
819	A	P	Flowrate Gas flowmeters	ספיקה מדוי ספיקה גזיים	[0.015 L/min to 50 L/min]	0.3%	Manufacturer instructions SOP 10007	Primary standard - Cal - Trak SL800 (*)
820	A	P, T			[0.015 L/min to 0.5 L/min]	1.1%	SOP 10047	Mass Flowmeters (*) (*) Calibration gas is N ₂ .
821	A	P, T			(0.5 L/min to 5 L/min)	0.7%		Volume flow rate may be presented in mass flow rate units at STP conditions, e.g. in SLPM
822	A	P, T			(5 L/min to 10 L/min)	0.5%		
823	A	P, T			(10 L/min to 50 L/min)	1.0%		Max pressure for calibration at P - 4.5 bar.
824	A	P1; T1			(0.1 L/min to 0.5 L/min)	1.1%		Max pressure for calibration at P1 - 413 bar.
825	A	P1; T1			(0.5 L/min to 5 L/min)	0.7%		
826	A	P1; T1			(5 L/min to 10 L/min)	0.5%		
827	A	P1; T1			(10 L/min to 200 L/min)	1.0%		
828	A	P1; T1			(200 L/min to 500 L/min)	1.4%		

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Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Physical Quantities - Mass					כיוול – גדלים פיזיקליים - מסה		
829	A	P	Mass, Weights	[1 mg to 1 g]	0.051 mg	ASTM-E-617 NIST Handbook 1&2-105	“METTLER” SG 32001
830	A	P		(1 g to 20 g]	0.07 mg	NIST Handbook 44	“METTLER” KCC150S
831	A	P		(20 g to 50 g]	0.07 mg	OIML IR No. R111,47,52	METTLER XP205
832	A	P		(50 g to 100 g]	0.043 mg	Manufacturer instructions	METTLER XP10002S
833	A	P		(100 g to 200 g]	0.075 mg	SOP 90150327	
834	A	P		(200 g to 10 kg]	0.027 g		
835	A	P		(10 kg to 32 kg]	0.66 g		
836	A	P		(32 kg to 150 kg]	11 g		
837	A	P;T	Mass Non-automatic weighing instruments Resolution 0.01 mg	[1 mg to 1 g]	0.013 mg	Euramet cg 18 Manufacturer instructions	The uncertainty quoted will depend on the performance of the weighing instrument under calibration and will depend on the calibration uncertainty of weights used. Available weights are: OIML Class E1 from 0.001 g to 500 g OIML Class E2 from 500 g to 4.5 kg OIML Class F1 from 4 kg to 135 kg NBS Handbook Class F from 50 kg to 350 kg
838	A	P;T		(1 g to 100 g]	0.023 mg	OIML 33	
839	A	P;T		(100 g to 200 g]	0.049 mg	NIST Handbook 1-105	
840	A	P;T	Mass Non-automatic weighing instruments Resolution 0.01 g	(200 g to 8 kg]	0.014 g	SOP 90150319	
841	A	P;T		(8 kg to 10 kg]	0.017 g		
842	A	P;T	Mass Non-automatic weighing instruments Resolution 0.1 g	(10 kg to 32 kg]	0.16 g		
843	A	T	Mass Non-automatic weighing instruments Resolution 1 g	(32 kg to 150 kg]	1.2 g		

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Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Physical Quantities - Mass					כיוול – גדלים פיזיקליים - מסה		
844	A	T	Mass Non-automatic weighing instruments Resolution 100 g	מסה, מאזניים לא אוטומטיים כושר הפרדה 100 g	(150 kg to 500 kg]	100 g	NBS Handbook Class F from 50 kg to 350 kg NBS Handbook Class F from 50 kg to 350 kg Test weights 5x 500 kg
845	A	T	Mass Non-automatic weighing instruments Resolution 500 g	מסה, מאזניים לא אוטומטיים כושר הפקדה 500 g	(500 kg to 2700 kg]	500 g	

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

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The certificate attached is an integral part of the schedule and is numbered identically להספד הזה ומספרה זהה למספר הנספח והתעודה המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח



Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 010

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Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Physical Quantities - Pressure					כיוול – גדלים פיזיקליים - לחץ		
846	A	T	Pneumatic pressure Absolute. Pressure indicating instruments and gauges	לחץ פניאומאטי, אבסולוטי מדדי לחץ פניאומאטיים	(10 kPa to 100 kPa]	0.88 Pa/kPa	Euramet cg 17 ASTM B40.100 BS EN 837 Manufacturer instructions SOP 90150317 SOP 10170 Comparison vs Druck 620, pressure generated by this instrument
847	A	T		(100 kPa to 700 kPa]	0.27 Pa/kPa		
848	A	T		(700 kPa to 68 MPa]	0.07 Pa/kPa		
849	A	T	Pneumatic pressure Gauge Pressure indicating instruments and gauges	לחץ פניאומאטי, יחסי מדדי לחץ פניאומאטיים	(2 MPa to 6 MPa] (6 MPa to 14 MPa] (14 MPa to 68 MPa]	0.2 Pa/kPa 0.13 Pa/kPa 0.08 Pa/kPa	Euramet cg 17 ASTM B40.100 BS EN 837 Manufacturer instructions SOP 90150314 SOP 10170
850	A	T					
851	A	T					
852	A	P	Hydraulic pressure, Gauge. Pressure indicating instruments and gauges	לחץ הידראולי מדדי לחץ הידראוליים	(69.1 MPa to 83 MPa] (83 MPa to 110 MPa] (110 MPa to 138 MPa] (138 MPa to 414 MPa]	66 kPa 84 kPa 100 kPa 290 kPa	ASME B40.100 EURAMET cg17 BS EN 837 Manufacturer instruction SOP 10006 Comparison vs. DWT BUDENBERG 283 A
853	A	P					
854	A	P					
855	A	P					
856	A	T	Hydraulic pressure, Gauge. Pressure indicating instruments and gauges	לחץ הידראולי מדדי לחץ	(0.2 MPa to 3.6 MPa] (3.6 MPa to 6.9 MPa] (6.9 MPa to 69 MPa]	20 kPa 42 kPa 43 kPa	SOP 10170 Comparison vs Druck 605, pressure generated by this instrument
857	A	T					
858	A	T					

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Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Physical Quantities - Temperature					כיוול – גדלים פיזיקליים - טמפרטורה		
859	A	P	Temperature. Resistance Thermometers טמפרטורה מדוי חום התנגדות	[-80 °C to -40 °C]	0.06 °C	IEC 60751 SOP 10003	SPRT Pt 100
860	A	P		[-40 °C to -10 °C]	0.04 °C		
861	A	P		[-10 °C to 50 °C]	0.03 °C		
862	A	P		0.01 °C (Triple point of water)	0.01 °C		
863	A	P		25 °C	0.015 °C		
864	A	P		[50 °C to 100 °C]	0.014 °C		
865	A	P		[100 °C to 150 °C]	0.05 °C		
866	A	P		[150 °C to 250 °C]	0.06 °C		
867	A	P		(250 °C to 420 °C)	0.13 °C		
868	A	P	(420 °C to 620 °C)	0.5 °C			
869	A	P	Temperature. Liquid in Glass Thermometers טמפרטורה מדוי חום, נוזל בזכוכית	[-80 °C to -40 °C]	0.4 °C	ASTM E77 SOP 9015039	Pt 100
870	A	P		[-40 °C to 100 °C]	0.13 °C		
871	A	P		0 °C	0.03 °C		
872	A	P		25 °C	0.05 °C		
873	A	P		(100 °C to 200 °C)	0.2 °C		

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Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 010

Schedule of Accreditation

Item	Scope Type	Site	Measurand Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Physical Quantities - Temperature					כיוול – גדלים פיזיקליים - טמפרטורה		
874	A	P		(200 °C to 400 °C)	0.45 °C		
875	A	P		(400 °C to 450 °C)	0.7 °C		
876	A	P	Temperature. Thermocouples, Noble Metal (S, R, ...)	0 °C (Ice point)	1.0 °C	ASTM-E-220	Pt 100 At ice point thermocouples in oil baths and fluidized bath vs. Pt.100
877	A	P	טמפרטורה צמדדים תרמיים, מתכות אצילות	[100 °C to 400 °C]	0.8 °C	ASTM-E-230	
878	A	P		(400 °C to 600 °C)	0.9 °C	Euramet cg8	
879	A	P		(600 °C to 1000 °C)	1.7 °C	SOP 9015038	
880	A	P	Temperature. Thermocouples Type B	100 °C to 1000 °C	1.7 °C	ASTM-E-220 ASTM-E-230 Euramet cg8 SOP 9015038	
881	A	P	Temperature. Base Thermocouples	0 °C (Ice point)	0.4 °C	ASTM-E-220 ASTM-E-230	Measurements by means of Pt 100 in oil baths and fluidized bath, Measurements by means of thermocouple type S in furnace
882	A	P	T, K, N, E, J	[-80 °C to 250 °C]	0.2 °C	Euramet cg8	
883	A	P		[250 °C to 300 °C]	0.3 °C	SOP 9015039	
884	A	P		[300 °C to 620 °C]	0.6 °C		
885	A	P		(620 °C to 1000 °C)	2 °C		
886	A	T	Temperature, Resistance Thermometers	[-25 °C to 140 °C]	0.4 °C	IEC 60751 SOP 9015039	Dry blocks calibrators Hart Scientific 9105 Pt 100, resistance meter Isotech bridge

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

Flexible scope in analytical tests: Type of matrix, analytes, experimental systems and/or analytical characteristics may be subject to changes, in accordance with the laboratory's approved and documented procedures. For details, please refer to the list of Accredited Tests, available from the laboratory upon request.

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The certificate attached is an integral part of the schedule and is numbered identically להסמכת מעבדות זהה למספר הנספח

